

<b>Notice of References Cited</b>	Application/Control No. 10/007,338		Applicant(s)/Patent Under Reexamination SYED, MAJID	
	Examiner Philip C. Lee		Art Unit 2152	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0073810	04-2006	Pyhalammi et al.	455/407
*	B	US-6,745,237	06-2004	Garritty et al.	709/219
*	C	US-6,822,954	11-2004	McConnell et al.	370/352
*	D	US-2003/0055977	03-2003	Miller, Michael J.	709/227
*	E	US-2002/0142763	10-2002	Kolsky, Amir David	455/419
*	F	US-7,046,691	05-2006	Kadyk et al.	370/466
*	G	US-2002/0146016	10-2002	Liu et al.	370/401
*	H	US-2004/0194131	09-2004	Ellis et al.	725/034
*	I	US-2003/0046670	03-2003	Marlow, Mark J.	717/140
*	J	US-2002/0095228	07-2002	Corts et al.	700/94
*	K	US-6,907,247	06-2005	Thompson et al.	455/450
*	L	US-2003/0014483	01-2003	Stevenson et al.	709/203
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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